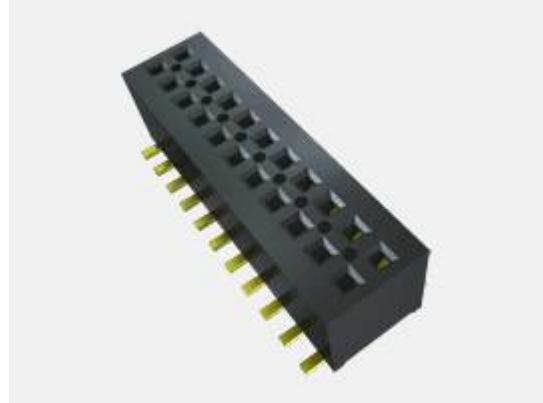


Project Number: Design Qualification Test Report	Tracking Code: 263526_Report_Rev_1
Requested by: Catie Eichhorn	Date: 11/22/2013
Part #: MLE-125-01-G-DV-A/FTMH-125-02-L-DV-A	
Part description: MLE/FTMH	Tech: Kason He
Test Start: 09/22/2013	Test Completed: 11/01/2013



## **DESIGN QUALIFICATION TEST REPORT**

**MLE/FTMH**  
**MLE-125-01-G-DV-A/FTMH-125-02-L-DV-A**

Tracking Code: 263526\_Report\_Rev\_1

Part #: MLE-125-01-G-DV-A/FTMH-125-02-L-DV-A

Part description: MLE/FTMH

## REVISION HISTORY

DATA	REV.NUM.	DESCRIPTION	ENG
11/22/2013	1	Initial Issue	KH

## CERTIFICATION

All instruments and measuring equipment were calibrated to National Institute for Standards and Technology (NIST) traceable standards according to ISO 10012-1 and ANSI/NCSL 2540-1, as applicable.

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## SCOPE

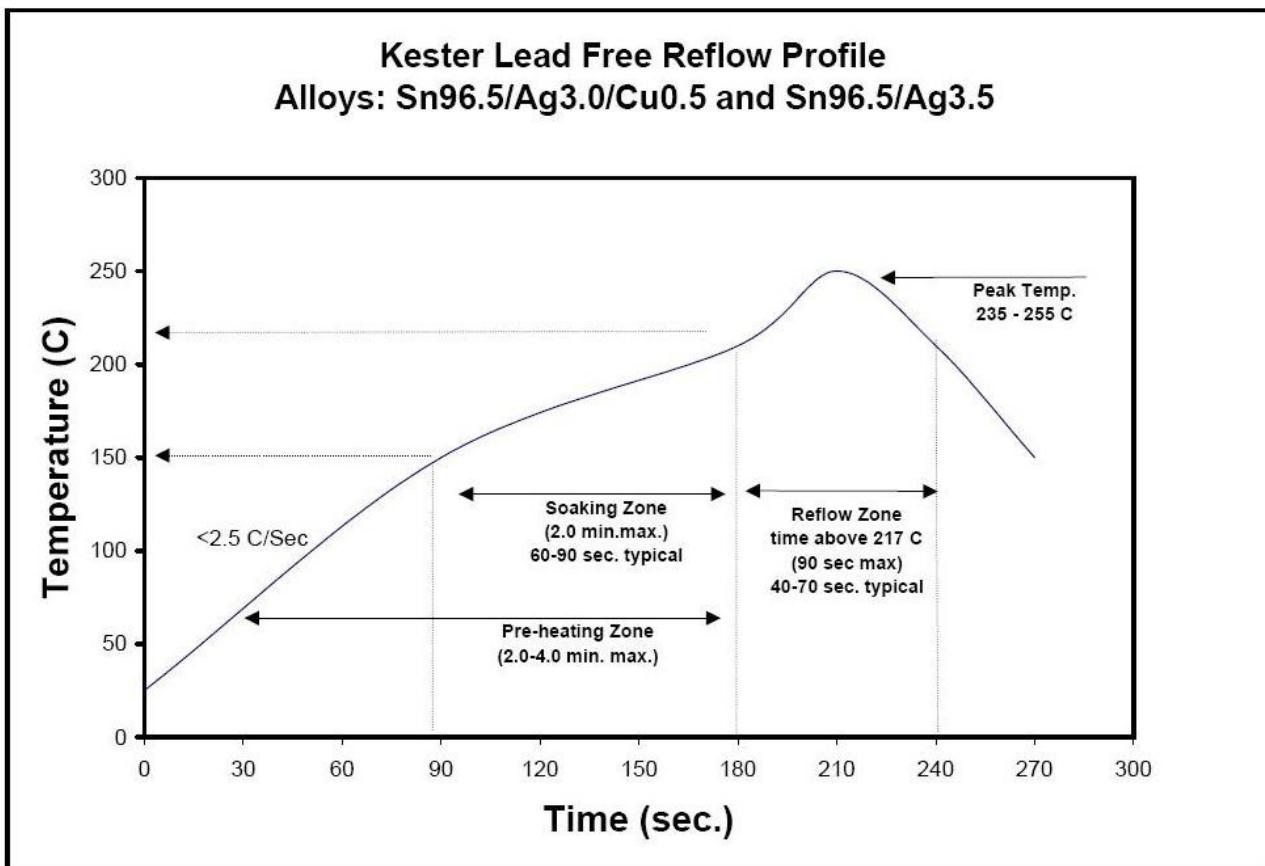
To perform the following tests: Design Qualification test. Please see test plan.

## APPLICABLE DOCUMENTS

Standards: EIA Publication 364

## TEST SAMPLES AND PREPARATION

- 1) All materials were manufactured in accordance with the applicable product specification.
- 2) All test samples were identified and encoded to maintain traceability throughout the test sequences.
- 3) After soldering, the parts to be used for LLCR testing were cleaned according to TLWI-0001.
- 4) Either an automated cleaning procedure or an ultrasonic cleaning procedure may be used.
- 5) The automated procedure is used with aqueous compatible soldering materials.
- 6) Parts not intended for testing LLCR are visually inspected and cleaned if necessary.
- 7) Any additional preparation will be noted in the individual test sequences.
- 8) Solder Information: Lead Free
- 9) Re-Flow Time/Temp: See accompanying profile.
- 10) Samtec Test PCBs used: PCB-105087-TST\PCB-105088-TST\PCB-105089-TST

**TYPICAL OVEN PROFILE (Soldering Parts to Test Boards)**

**FLOWCHARTS****Gas Tight**Group 1

MLE-125-01-G-DV-A

FTMH-125-02-L-DV-A

8 Assemblies

**Step    Description**

1. LLCR <sup>(2)</sup>  
Max Delta = 15 mOhm
2. Gas Tight <sup>(1)</sup>
3. LLCR <sup>(2)</sup>  
Max Delta = 15 mOhm

(1) Gas Tight = EIA-364-36

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max  
Test Current = 100 mA Max

**Normal Force**Group 1

MLE-125-01-G-DV-A

FTMH-125-02-L-DV-A

8 Contacts Minimum

Signal Without Thermals

Group 2

MLE-125-01-G-DV-A

FTMH-125-02-L-DV-A

8 Contacts Minimum

Signal With Thermals

**Step    Description**

1. Contact Gaps
2. Normal Force <sup>(1)</sup>  
Deflection = 0.005 "  
Expected Force at Max Deflection = 54 g

**Step    Description**

1. Contact Gaps
2. Thermal Age <sup>(2)</sup>
3. Contact Gaps
4. Normal Force <sup>(1)</sup>  
Deflection = 0.005 "  
Expected Force at Max Deflection = 54 g

(1) Normal Force = EIA-364-04

(2) Thermal Age = EIA-364-17

Test Condition = 4 (105°C)

Time Condition = B (250 Hours)

**FLOWCHARTS Continued****Thermal Aging****Group 1**

MLE-125-01-G-DV-A

FTMH-125-02-L-DV-A

8 Assemblies

**Step    Description**

1. Contact Gaps
2. Mating/Unmating Force <sup>(2)</sup>
3. LLCR <sup>(1)</sup>  
Max Delta = 15 mOhm
4. Thermal Age <sup>(3)</sup>
5. LLCR <sup>(1)</sup>  
Max Delta = 15 mOhm
6. Mating/Unmating Force <sup>(2)</sup>
7. Contact Gaps

---

(1) LLCR = EIA-364-23  
Open Circuit Voltage = 20 mV Max  
Test Current = 100 mA Max

(2) Mating/Unmating Force = EIA-364-13

(3) Thermal Age = EIA-364-17  
Test Condition = 4 (105°C)  
Time Condition = B (250 Hours)

## FLOWCHARTS Continued

Mating/Unmating/Durability

Group 1		Group 2		Group 3	
MLE-125-01-G-DV-A		MLE-105-01-G-DV-A		MLE-150-01-G-DV-A	
FTMH-125-02-L-DV-A		FTMH-105-02-L-DV-A		FTMH-150-02-L-DV-A	
8 Assemblies		8 Assemblies		8 Assemblies	
Step	Description	Step	Description	Step	Description
1.	Contact Gaps	1.	Contact Gaps	1.	Contact Gaps
2.	LLCR (2) Max Delta = 15 mOhm	2.	Mating/Unmating Force (3)	2.	Mating/Unmating Force (3)
3.	Mating/Unmating Force (3)	3.	Cycles Quantity = 25 Cycles	3.	Cycles Quantity = 25 Cycles
4.	Cycles Quantity = 25 Cycles	4.	Mating/Unmating Force (3)	4.	Mating/Unmating Force (3)
5.	Mating/Unmating Force (3)	5.	Cycles Quantity = 25 Cycles	5.	Cycles Quantity = 25 Cycles
6.	Cycles Quantity = 25 Cycles	6.	Mating/Unmating Force (3)	6.	Mating/Unmating Force (3)
7.	Mating/Unmating Force (3)	7.	Cycles Quantity = 25 Cycles	7.	Cycles Quantity = 25 Cycles
8.	Cycles Quantity = 25 Cycles	8.	Mating/Unmating Force (3)	8.	Mating/Unmating Force (3)
9.	Mating/Unmating Force (3)	9.	Cycles Quantity = 25 Cycles	9.	Cycles Quantity = 25 Cycles
10.	Cycles Quantity = 25 Cycles	10.	Mating/Unmating Force (3)	10.	Mating/Unmating Force (3)
11.	Mating/Unmating Force (3)				
12.	Contact Gaps				
13.	LLCR (2) Max Delta = 15 mOhm				
14.	Thermal Shock (4)				
15.	LLCR (2) Max Delta = 15 mOhm				
16.	Humidity (1)				
17.	LLCR (2) Max Delta = 15 mOhm				
18.	Mating/Unmating Force (3)				

(1) Humidity = EIA-364-31

Test Condition = B (240 Hours)

Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)

Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(2) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max

Test Current = 100 mA Max

(3) Mating/Unmating Force = EIA-364-13

(4) Thermal Shock = EIA-364-32

Exposure Time at Temperature Extremes = 1/2 Hour

Method A, Test Condition = I (-55°C to +85°C)

Test Duration = A-3 (100 Cycles)

## FLOWCHARTS Continued

### IR/DWV

#### Pin-to-Pin

Group 1		Group 2		Group 3		Group 4	
MLE-125-01-G-DV-A FTMH-125-02-L-DV-A 2 Assemblies		MLE-125-01-G-DV-A 2 Assemblies		FTMH-125-02-L-DV-A 2 Assemblies		MLE-125-01-G-DV-A FTMH-125-02-L-DV-A 2 Assemblies	
<b>Step</b>	<b>Description</b>	<b>Step</b>	<b>Description</b>	<b>Step</b>	<b>Description</b>	<b>Step</b>	<b>Description</b>
1.	DWV Breakdown <sup>(2)</sup>	1.	DWV Breakdown <sup>(2)</sup>	1.	DWV Breakdown <sup>(2)</sup>	1.	IR <sup>(4)</sup>
							DWV at Test Voltage <sup>(1)</sup>
							Thermal Shock <sup>(5)</sup>
							IR <sup>(4)</sup>
							DWV at Test Voltage <sup>(1)</sup>
							Humidity <sup>(3)</sup>
							IR <sup>(4)</sup>
							DWV at Test Voltage <sup>(1)</sup>

#### Row-to-Row

Group 5		Group 6		Group 7		Group 8	
MLE-125-01-G-DV-A FTMH-125-02-L-DV-A 2 Assemblies		MLE-125-01-G-DV-A 2 Assemblies		FTMH-125-02-L-DV-A 2 Assemblies		MLE-125-01-G-DV-A FTMH-125-02-L-DV-A 2 Assemblies	
<b>Step</b>	<b>Description</b>	<b>Step</b>	<b>Description</b>	<b>Step</b>	<b>Description</b>	<b>Step</b>	<b>Description</b>
1.	DWV Breakdown <sup>(2)</sup>	1.	DWV Breakdown <sup>(2)</sup>	1.	DWV Breakdown <sup>(2)</sup>	1.	IR <sup>(4)</sup>
							DWV at Test Voltage <sup>(1)</sup>
							Thermal Shock <sup>(5)</sup>
							IR <sup>(4)</sup>
							DWV at Test Voltage <sup>(1)</sup>
							Humidity <sup>(3)</sup>
							IR <sup>(4)</sup>
							DWV at Test Voltage <sup>(1)</sup>

(1) DWV at Test Voltage = EIA-364-20

Test Condition = 1 (Sea Level)

DWV test voltage is equal to 75% of the lowest breakdown voltage

Test voltage applied for 60 seconds

(2) DWV Breakdown = EIA-364-20

Test Condition = 1 (Sea Level)

DWV test voltage is equal to 75% of the lowest breakdown voltage

Test voltage applied for 60 seconds

(3) Humidity = EIA-364-31

Test Condition = B (240 Hours)

Test Method = III (+25°C to +65°C @ 90% RH to 98% RH)

Test Exceptions: ambient pre-condition and delete steps 7a and 7b

(4) IR = EIA-364-21

Test Condition = 500 Vdc, 2 Minutes Max

(5) Thermal Shock = EIA-364-32

Exposure Time at Temperature Extremes = 1/2 Hour

Method A, Test Condition = I (-55°C to +85°C)

Test Duration = A-3 (100 Cycles)

## FLOWCHARTS Continued

Current Carrying Capacity

Group 1  
 MLE-150-01-G-DV-A  
 FTMH-150-02-L-DV-A  
 2 Pins Powered  
 Signal

**Step** **Description**  
 1. CCC (1)  
 Rows = 2  
 Number of Positions = 1

Group 2  
 MLE-150-01-G-DV-A  
 FTMH-150-02-L-DV-A  
 4 Pins Powered  
 Signal

**Step** **Description**  
 1. CCC (1)  
 Rows = 2  
 Number of Positions = 2

Group 3  
 MLE-150-01-G-DV-A  
 FTMH-150-02-L-DV-A  
 6 Pins Powered  
 Signal

**Step** **Description**  
 1. CCC (1)  
 Rows = 2  
 Number of Positions = 3

Group 5  
 MLE-150-01-G-DV-A  
 FTMH-150-02-L-DV-A  
 100 Pins Powered  
 Signal

**Step** **Description**  
 1. CCC (1)  
 Rows = 2  
 Number of Positions = 50

(1) CCC = EIA-364-70

Method 2, Temperature Rise Versus Current Curve

(TIN PLATING) - Tabulate calculated current at RT, 65°C, 75°C and 95°C after derating 20% and based on 105°C

(GOLD PLATING) - Tabulate calculated current at RT, 85°C, 95°C and 115°C after derating 20% and based on 125°C

**FLOWCHARTS Continued****Mechanical Shock/Random Vibration/LLCR**Group 1

MLE-125-01-G-DV-A

FTMH-125-02-L-DV-A

8 Assemblies

**Step Description**

1. LLCR<sup>(1)</sup>  
Max Delta = 15 mOhm
2. Mechanical Shock<sup>(2)</sup>
3. Random Vibration<sup>(3)</sup>
4. LLCR<sup>(1)</sup>  
Max Delta = 15 mOhm

(1) LLCR = EIA-364-23

Open Circuit Voltage = 20 mV Max  
Test Current = 100 mA Max

(2) Mechanical Shock = EIA-364-27

Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)  
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(3) Random Vibration = EIA-364-28

Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

**Mechanical Shock/Random Vibration/Event Detection**Group 1

MLE-125-01-G-DV-A

FTMH-125-02-L-DV-A

60 Points

**Step Description**

1. Nanosecond Event Detection  
(Mechanical Shock)<sup>(1)</sup>
2. Nanosecond Event Detection  
(Random Vibration)<sup>(2)</sup>

(1) Nanosecond Event Detection (Mechanical Shock)

Use EIA-364-87 for Nanosecond Event Detection:  
Test Condition = F (50 nanoseconds at 10 ohms)  
Use EIA-364-27 for Mechanical Shock:  
Test Condition = C (100 G Peak, 6 milliseconds, Half Sine)  
Number of Shocks = 3 Per Direction, Per Axis, 18 Total

(2) Nanosecond Event Detection (Random Vibration)

Use EIA-364-87 for Nanosecond Event Detection:  
Test Condition = F (50 nanoseconds at 10 ohms)  
Use EIA-364-28 for Random Vibration:  
Condition = VB (7.56 gRMS Average, 2 Hours/Axis)

## ATTRIBUTE DEFINITIONS

The following is a brief, simplified description of attributes.

### **THERMAL SHOCK:**

- 1) EIA-364-32, *Thermal Shock (Temperature Cycling) Test Procedure for Electrical Connectors*.
- 2) Test Condition 1: -55°C to +85°C
- 3) Test Time: ½ hour dwell at each temperature extreme
- 4) Number of Cycles: 100
- 5) All test samples are pre-conditioned at ambient.
- 6) All test samples are exposed to environmental stressing in the mated condition.

### **THERMAL:**

- 1) EIA-364-17, *Temperature Life with or without Electrical Load Test Procedure for Electrical Connectors*.
- 2) Test Condition 4 at 105° C
- 3) Test Time Condition B for 250 hours.
- 4) All test samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

### **HUMIDITY:**

- 1) Reference document: EIA-364-31, *Humidity Test Procedure for Electrical Connectors*.
- 2) Test Condition B, 240 Hours.
- 3) Method III, +25° C to + 65° C, 90% to 98% Relative Humidity excluding sub-cycles 7a and 7b.
- 4) All samples are pre-conditioned at ambient.
- 5) All test samples are exposed to environmental stressing in the mated condition.

### **MECHANICAL SHOCK (Specified Pulse):**

- 1) Reference document: EIA-364-27, *Mechanical Shock Test Procedure for Electrical Connectors*
- 2) Test Condition C
- 3) Peak Value: 100 G
- 4) Duration: 6 Milliseconds
- 5) Wave Form: Half Sine
- 6) Velocity: 12.3 ft/s
- 7) Number of Shocks: 3 Shocks / Direction, 3 Axis (18 Total)

### **VIBRATION:**

- 1) Reference document: EIA-364-28, *Vibration Test Procedure for Electrical Connectors*
- 2) Test Condition V, Letter B
- 3) Power Spectral Density: 0.04 G<sup>2</sup> / Hz
- 4) G 'RMS': 7.56
- 5) Frequency: 50 to 2000 Hz
- 6) Duration: 2.0 Hours per axis (3 axis total)

### **NANOSECOND-EVENT DETECTION:**

- 1) Reference document: EIA-364-87, *Nanosecond-Event Detection for Electrical Connectors*
- 2) Prior to test, the samples were characterized to assure the low nanosecond event being monitored will trigger the detector.
- 3) After characterization it was determined the test samples could be monitored for 50 nanosecond events

### **MATING/UNMATING:**

- 1) Reference document: EIA-364-13, *Mating and Unmating Forces Test Procedure for Electrical Connectors*.
- 2) The full insertion position was to within 0.003" to 0.004" of the plug bottoming out in the receptacle to prevent damage to the system under test.
- 3) One of the mating parts is secured to a floating X-Y table to prevent damage during cycling.

## ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

### TEMPERATURE RISE (Current Carrying Capacity, CCC):

- 1) EIA-364-70, *Temperature Rise versus Current Test Procedure for Electrical Connectors and Sockets*.
- 2) When current passes through a contact, the temperature of the contact increases as a result of  $I^2R$  (resistive) heating.
- 3) The number of contacts being investigated plays a significant part in power dissipation and therefore temperature rise.
- 4) The size of the temperature probe can affect the measured temperature.
- 5) Copper traces on PC boards will contribute to temperature rise:
  - a. Self heating (resistive)
  - b. Reduction in heat sink capacity affecting the heated contacts
- 6) A de-rating curve, usually 20%, is calculated.
- 7) Calculated de-rated currents at three temperature points are reported:
  - a. Ambient
  - b.  $85^{\circ}\text{C}$
  - c.  $95^{\circ}\text{C}$
  - d.  $115^{\circ}\text{C}$
- 8) Typically, neighboring contacts (in close proximity to maximize heat build up) are energized.
- 9) The thermocouple (or temperature measuring probe) will be positioned at a location to sense the maximum temperature in the vicinity of the heat generation area.
- 10) A computer program, *TR 803.exe*, ensures accurate stability for data acquisition.
- 11) Hook-up wire cross section is larger than the cross section of any connector leads/PC board traces, jumpers, etc.
- 12) Hook-up wire length is longer than the minimum specified in the referencing standard.

### LLCR:

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
  - a.  $\leq +5.0 \text{ mOhms}$ : ----- Stable
  - b.  $+5.1 \text{ to } +10.0 \text{ mOhms}$ : ----- Minor
  - c.  $+10.1 \text{ to } +15.0 \text{ mOhms}$ : ----- Acceptable
  - d.  $+15.1 \text{ to } +50.0 \text{ mOhms}$ : ----- Marginal
  - e.  $+50.1 \text{ to } +2000 \text{ mOhms}$ : ----- Unstable
  - f.  $>+2000 \text{ mOhms}$ : ----- Open Failure

## ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes.

### GAS TIGHT:

To provide method for evaluating the ability of the contacting surfaces in preventing penetration of harsh vapors which might lead to oxide formation that may degrade the electrical performance of the contact system.

- 1) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 2) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 3) The following guidelines are used to categorize the changes in LLCR as a result from stressing
  - a.  $\leq +5.0$  mOhms:----- Stable
  - b.  $+5.1$  to  $+10.0$  mOhms:----- Minor
  - c.  $+10.1$  to  $+15.0$  mOhms:----- Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms:----- Marginal
  - e.  $+50.1$  to  $+2000$  mOhms:----- Unstable
  - f.  $>+2000$  mOhms:----- Open Failure
- 4) Procedure:
  - a. Reference document: EIA-364-36, *Test Procedure for Determination of Gas-Tight Characteristics for Electrical Connectors, Sockets and/or Contact Systems*.
  - b. Test Conditions:
    - i. Class II--- Mated pairs of contacts assembled to their plastic housings.
    - ii. Reagent grade Nitric Acid shall be used of sufficient volume to saturate the test chamber
    - iii. The ratio of the volume of the test chamber to the surface area of the acid shall be 10:1.
    - iv. The chamber shall be saturated with the vapor for at least 15 minutes before samples are added.
    - v. Exposure time, 55 to 65 minutes.
    - vi. The samples shall be no closer to the chamber walls than 1 inches and no closer to the surface of the acid than 3 inches.
    - vii. The samples shall be dried after exposure for a minimum of 1 hour.
    - viii. Drying temperature  $50^{\circ}\text{C}$
    - ix. The final LLCR shall be conducted within 1 hour after drying.

## ATTRIBUTE DEFINITIONS Continued

The following is a brief, simplified description of attributes

### **NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):**

- 1) Reference document: EIA-364-04, *Normal Force Test Procedure for Electrical Connectors*.
- 2) The contacts shall be tested in the connector housing.
- 3) If necessary, a “window” shall be made in the connector body to allow a probe to engage and deflect the contact at the same attitude and distance (plus 0.05 mm [0.002”]) as would occur in actual use.
- 4) The connector housing shall be placed in a holding fixture that does not interfere with or otherwise influence the contact force or deflection.
- 5) Said holding fixture shall be mounted on a floating, adjustable, X-Y table on the base of the Dillon TC<sup>2</sup>, computer controlled test stand with a deflection measurement system accuracy of 5.0  $\mu\text{m}$  (0.0002”).
- 6) The nominal deflection rate shall be 5 mm (0.2”)/minute.
- 7) Unless otherwise noted a minimum of five contacts shall be tested.
- 8) The force/deflection characteristic to load and unload each contact shall be repeated five times.
- 9) The system shall utilize the TC<sup>2</sup> software in order to acquire and record the test data.
- 10) The permanent set of each contact shall be measured within the TC<sup>2</sup> software.
- 11) The acquired data shall be graphed with the deflection data on the X-axis and the force data on the Y-axis and a print out will be stored with the Tracking Code paperwork.

### **INSULATION RESISTANCE (IR):**

To determine the resistance of insulation materials to leakage of current through or on the surface of these materials when a DC potential is applied.

- 1) **PROCEDURE:**
  - a. Reference document: EIA-364-21, *Insulation Resistance Test Procedure for Electrical Connectors*.
  - b. Test Conditions:
    - i. Between Adjacent Contacts or Signal-to-Ground
    - ii. Electrification Time 2.0 minutes
    - iii. Test Voltage (500 VDC) corresponds to calibration settings for measuring resistances.
- 2) **MEASUREMENTS:**
- 3) When the specified test voltage is applied (VDC), the insulation resistance shall not be less than 5000 megohms.

### **DIELECTRIC WITHSTANDING VOLTAGE (DWV):**

To determine if the sockets can operate at its rated voltage and withstand momentary over potentials due to switching, surges, and other similar phenomenon. Separate samples are used to evaluate the effect of environmental stresses so not to influence the readings from arcing that occurs during the measurement process.

- 1) **PROCEDURE:**
  - a. Reference document: EIA-364-20, *Withstanding Voltage Test Procedure for Electrical Connectors*.
  - b. Test Conditions:
    - i. Between Adjacent Contacts or Signal-to-Ground
    - ii. Barometric Test Condition 1
    - iii. Rate of Application 500 V/Sec
    - iv. Test Voltage (VAC) until breakdown occurs
- 2) **MEASUREMENTS/CALCULATIONS**
  - a. The breakdown voltage shall be measured and recorded.
  - b. The dielectric withstanding voltage shall be recorded as 75% of the minimum breakdown voltage.
  - c. The working voltage shall be recorded as one-third (1/3) of the dielectric withstanding voltage (one-fourth of the breakdown voltage).

## RESULTS

### Temperature Rise, CCC at a 20% de-rating

- CCC for a 30°C Temperature Rise ----- 2.9 A per contact with 2 contacts powered
- CCC for a 30°C Temperature Rise ----- 2.1 A per contact with 4 contacts powered
- CCC for a 30°C Temperature Rise ----- 1.7 A per contact with 6 contacts powered
- CCC for a 30°C Temperature Rise ----- 1.5 A per contact with 8 contacts powered
- CCC for a 30°C Temperature Rise ----- 0.8 A per contact with all contacts powered

### Mating – Unmating Forces

#### Thermal Aging Group

- Initial
  - Mating
    - Min ----- 3.40 Lbs
    - Max ----- 4.12 Lbs
  - Unmating
    - Min ----- 1.56 Lbs
    - Max ----- 2.38 Lbs
- After Thermal
  - Mating
    - Min ----- 2.24 Lbs
    - Max ----- 2.66 Lbs
  - Unmating
    - Min ----- 1.24 Lbs
    - Max ----- 1.75 Lbs

## RESULTS Continued

### Mating – Unmating Forces

#### Mating-Unmating Durability Group

- Initial
  - Mating
    - Min ----- 2.98 Lbs
    - Max----- 3.87 Lbs
  - Unmating
    - Min ----- 1.56 Lbs
    - Max----- 2.42 Lbs
- After 25 Cycles
  - Mating
    - Min ----- 3.17 Lbs
    - Max----- 4.91 Lbs
  - Unmating
    - Min ----- 2.07 Lbs
    - Max----- 3.68 Lbs
- After 50 Cycles
  - Mating
    - Min ----- 3.20 Lbs
    - Max----- 5.50 Lbs
  - Unmating
    - Min ----- 2.19 Lbs
    - Max----- 4.16 Lbs
- After 75 Cycles
  - Mating
    - Min ----- 3.21 Lbs
    - Max----- 5.95 Lbs
  - Unmating
    - Min ----- 2.43 Lbs
    - Max----- 4.58 Lbs
- After 100 Cycles
  - Mating
    - Min ----- 3.34 Lbs
    - Max----- 6.41 Lbs
  - Unmating
    - Min ----- 2.46 Lbs
    - Max----- 4.77 Lbs
- Humidity
  - Mating
    - Min ----- 2.24 Lbs
    - Max----- 3.24 Lbs
  - Unmating
    - Min ----- 1.51 Lbs
    - Max----- 2.75 Lbs

## RESULTS Continued

### Mating – Unmating Forces

#### Mating-Unmating Basic (MLE-150-01-G-DV-A/FTMH-150-02-L-DV-A)

- **Initial**
  - **Mating**
    - Min ----- **8.57 Lbs**
    - Max----- **10.40 Lbs**
  - **Unmating**
    - Min ----- **4.05 Lbs**
    - Max----- **5.38 Lbs**
- **After 25 Cycles**
  - **Mating**
    - Min ----- **8.94 Lbs**
    - Max----- **13.36 Lbs**
  - **Unmating**
    - Min ----- **6.38 Lbs**
    - Max----- **9.29 Lbs**
- **After 50 Cycles**
  - **Mating**
    - Min ----- **9.43 Lbs**
    - Max----- **13.58 Lbs**
  - **Unmating**
    - Min ----- **7.01 Lbs**
    - Max----- **10.21 Lbs**
- **After 75 Cycles**
  - **Mating**
    - Min ----- **10.17 Lbs**
    - Max----- **14.02 Lbs**
  - **Unmating**
    - Min ----- **7.38 Lbs**
    - Max----- **10.17 Lbs**
- **After 100 Cycles**
  - **Mating**
    - Min ----- **10.61 Lbs**
    - Max----- **14.71 Lbs**
  - **Unmating**
    - Min ----- **7.71 Lbs**
    - Max----- **10.83 Lbs**

## RESULTS Continued

### Mating – Unmating Forces

#### Mating-Unmating Basic (MLE-105-01-G-DV-A/FTMH-105-02-L-DV-A)

- Initial
  - Mating
    - Min ----- 0.62 Lbs
    - Max ----- 0.84 Lbs
  - Unmating
    - Min ----- 0.31 Lbs
    - Max ----- 0.42 Lbs
- After 25 Cycles
  - Mating
    - Min ----- 0.63 Lbs
    - Max ----- 0.89 Lbs
  - Unmating
    - Min ----- 0.43 Lbs
    - Max ----- 0.66 Lbs
- After 50 Cycles
  - Mating
    - Min ----- 0.64 Lbs
    - Max ----- 0.94 Lbs
  - Unmating
    - Min ----- 0.49 Lbs
    - Max ----- 0.72 Lbs
- After 75 Cycles
  - Mating
    - Min ----- 0.69 Lbs
    - Max ----- 1.00 Lbs
  - Unmating
    - Min ----- 0.54 Lbs
    - Max ----- 0.81 Lbs
- After 100 Cycles
  - Mating
    - Min ----- 0.75 Lbs
    - Max ----- 1.04 Lbs
  - Unmating
    - Min ----- 0.60 Lbs
    - Max ----- 0.83 Lbs

### Normal Force at 0.0055 inch deflection

- Initial
  - Min ----- 135.20 gf
  - Max ----- 150.50 gf
- Thermal
  - Min ----- 132.50 gf
  - Max ----- 167.90 gf

<ul style="list-style-type: none"> <li>Set ----- 0.0003 in</li> <li>Set ----- 0.0008 in</li> </ul>	<ul style="list-style-type: none"> <li>Set ----- 0.0000 in</li> <li>Set ----- 0.0007 in</li> </ul>
--	--

## RESULTS Continued

### Insulation Resistance minimums, IR

#### Pin to Pin

- Initial
  - Mated ----- 10000 Meg Ω ----- Passed
  - Unmated ----- 10000 Meg Ω ----- Passed
- Thermal Shock
  - Mated ----- 10000 Meg Ω ----- Passed
  - Unmated ----- 10000 Meg Ω ----- Passed
- Humidity
  - Mated ----- 10000 Meg Ω ----- Passed
  - Unmated ----- 10000 Meg Ω ----- Passed

#### Row to Row

- Initial
  - Mated ----- 10000 Meg Ω ----- Passed
  - Unmated ----- 10000 Meg Ω ----- Passed
- Thermal Shock
  - Mated ----- 10000 Meg Ω ----- Passed
  - Unmated ----- 10000 Meg Ω ----- Passed
- Humidity
  - Mated ----- 10000 Meg Ω ----- Passed
  - Unmated ----- 10000 Meg Ω ----- Passed

### Dielectric Withstanding Voltage minimums, DWV

#### Minumums

- Breakdown Voltage ----- 1250 VAC
- Test Voltage ----- 938 VAC
- Working Voltage ----- 310 VAC

#### Pin to Pin

- Initial DWV ----- Passed
- Thermal DWV ----- Passed
- Humidity DWV ----- Passed

#### Row to Row

- Initial DWV ----- Passed
- Thermal DWV ----- Passed
- Humidity DWV ----- Passed

## RESULTS Continued

### LLCR Thermal Aging Group (192 LLCR test points)

- Initial ----- 14.37 mOhms Max
- Thermal
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
  - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
  - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
  - >+2000 mOhms ----- 0 Points ----- Open Failure

### LLCR Mating/Unmating Durability Group (192 LLCR test points)

- Initial ----- 13.59 mOhms Max
- Durability, 100 Cycles
  - <= +5.0 mOhms ----- 183 Points ----- Stable
  - +5.1 to +10.0 mOhms ----- 9 Points ----- Minor
  - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
  - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
  - >+2000 mOhms ----- 0 Points ----- Open Failure
- Thermal Shock
  - <= +5.0 mOhms ----- 186 Points ----- Stable
  - +5.1 to +10.0 mOhms ----- 6 Points ----- Minor
  - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
  - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
  - >+2000 mOhms ----- 0 Points ----- Open Failure
- Humidity
  - <= +5.0 mOhms ----- 173 Points ----- Stable
  - +5.1 to +10.0 mOhms ----- 19 Points ----- Minor
  - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
  - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
  - >+2000 mOhms ----- 0 Points ----- Open Failure

### LLCR Gas Tight Group (192 LLCR test points)

- Initial ----- 13.92 mOhms Max
- Gas-Tight
  - <= +5.0 mOhms ----- 190 Points ----- Stable
  - +5.1 to +10.0 mOhms ----- 2 Points ----- Minor
  - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
  - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
  - >+2000 mOhms ----- 0 Points ----- Open Failure

## RESULTS Continued

### LLCR Shock & Vibration Group (192 LLCR test points)

- Initial ----- 10.41 mOhms Max
- Shock & Vibration
  - <= +5.0 mOhms ----- 192 Points ----- Stable
  - +5.1 to +10.0 mOhms ----- 0 Points ----- Minor
  - +10.1 to +15.0 mOhms ----- 0 Points ----- Acceptable
  - +15.1 to +50.0 mOhms ----- 0 Points ----- Marginal
  - +50.1 to +2000 mOhms ----- 0 Points ----- Unstable
  - >+2000 mOhms ----- 0 Points ----- Open Failure

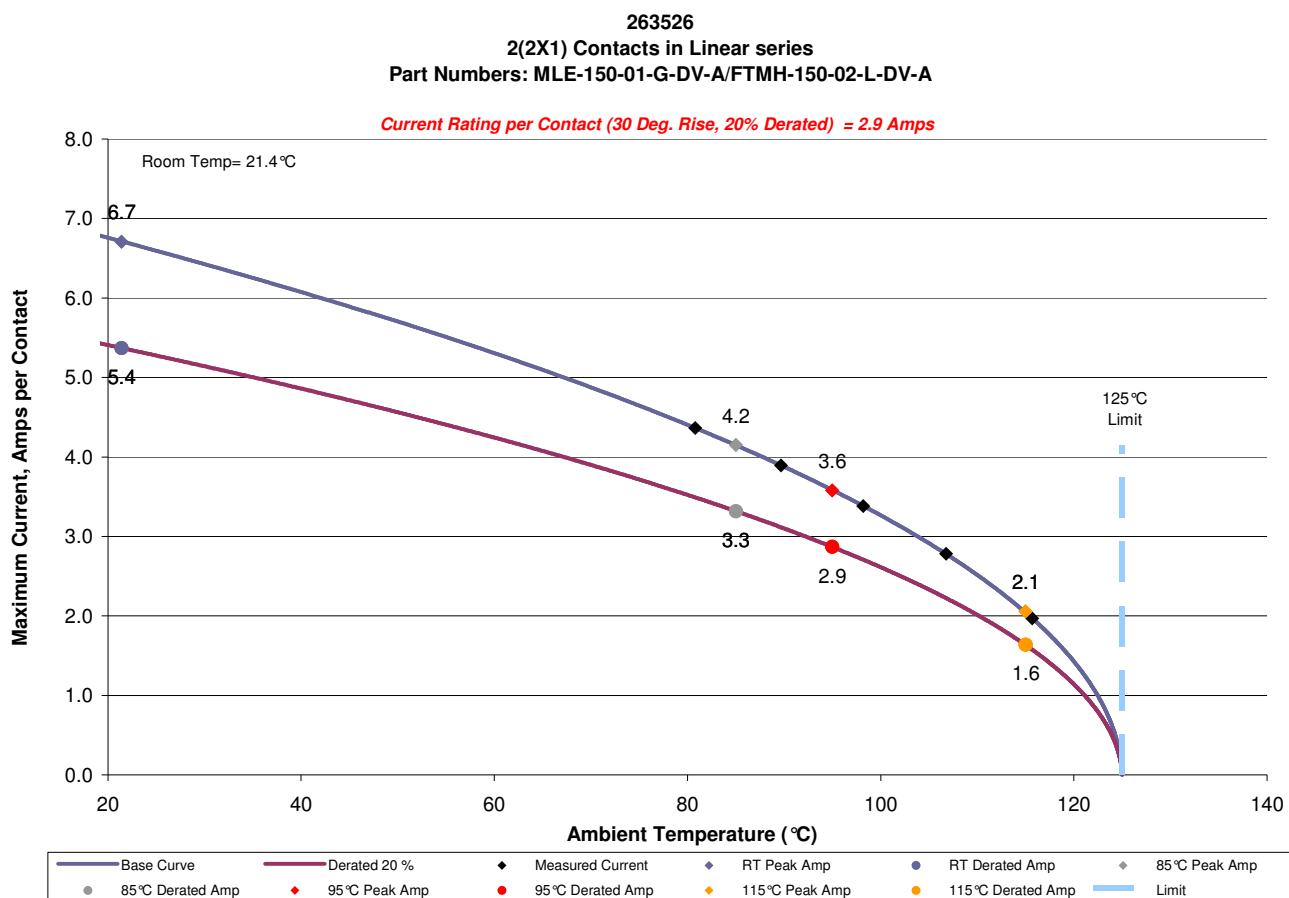
### Mechanical Shock & Random Vibration:

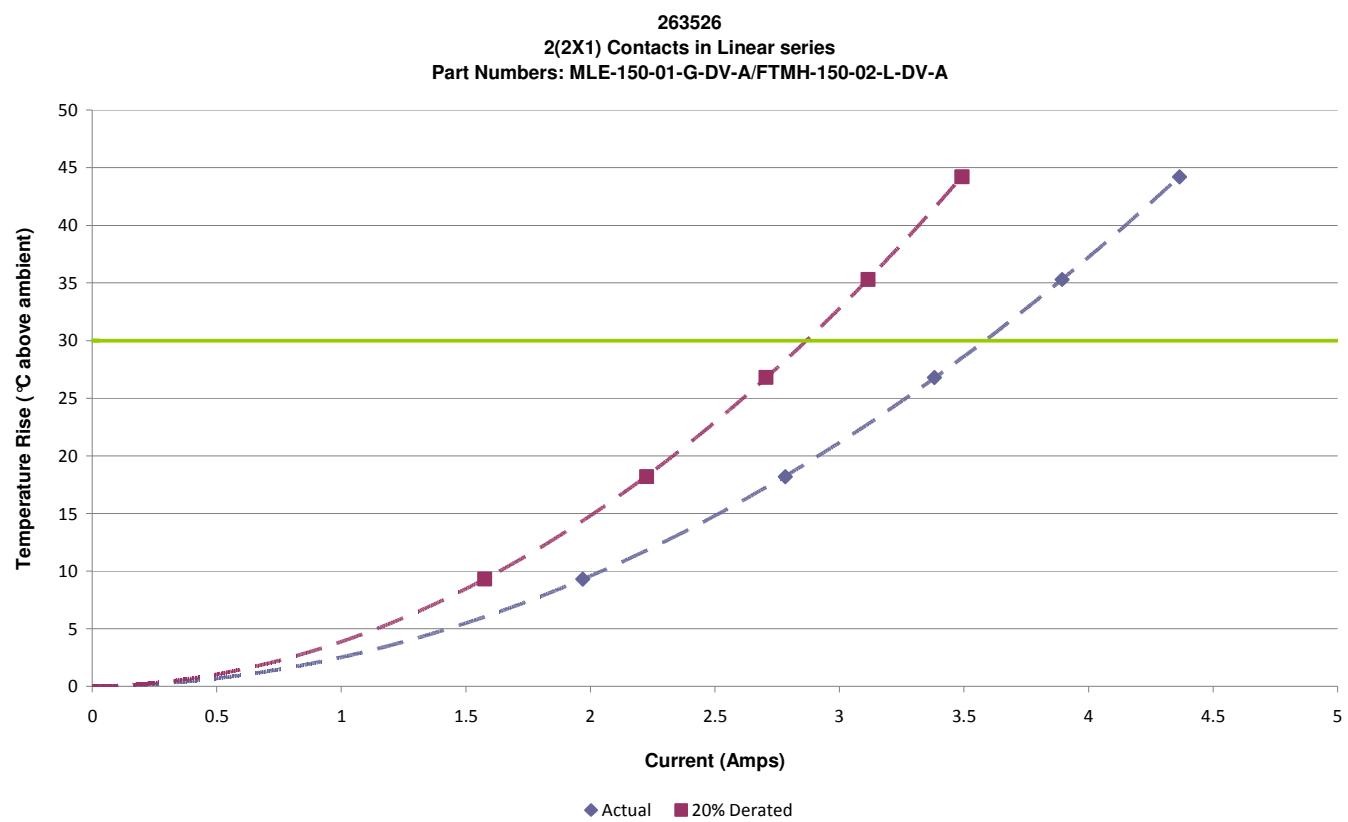
- Shock
  - No Damage----- ----- Pass
  - 50 Nanoseconds----- ----- Pass
- Vibration
  - No Damage----- ----- Pass
  - 50 Nanoseconds----- ----- Pass

## DATA SUMMARIES

### TEMPERATURE RISE (Current Carrying Capacity, CCC):

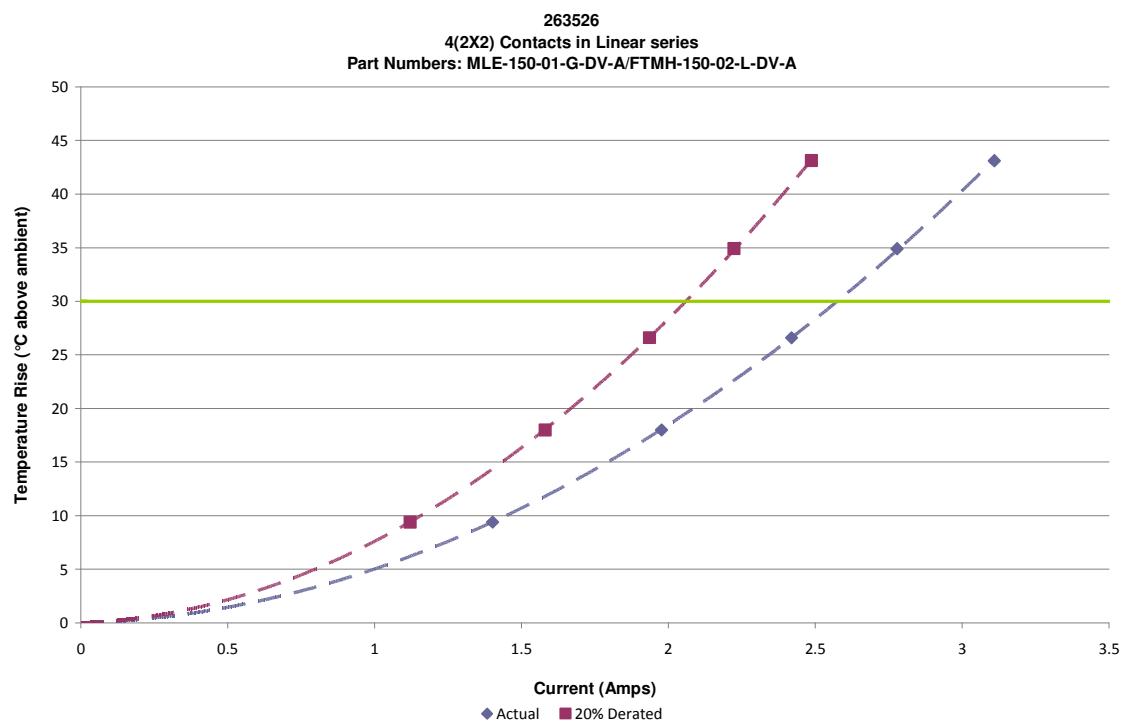
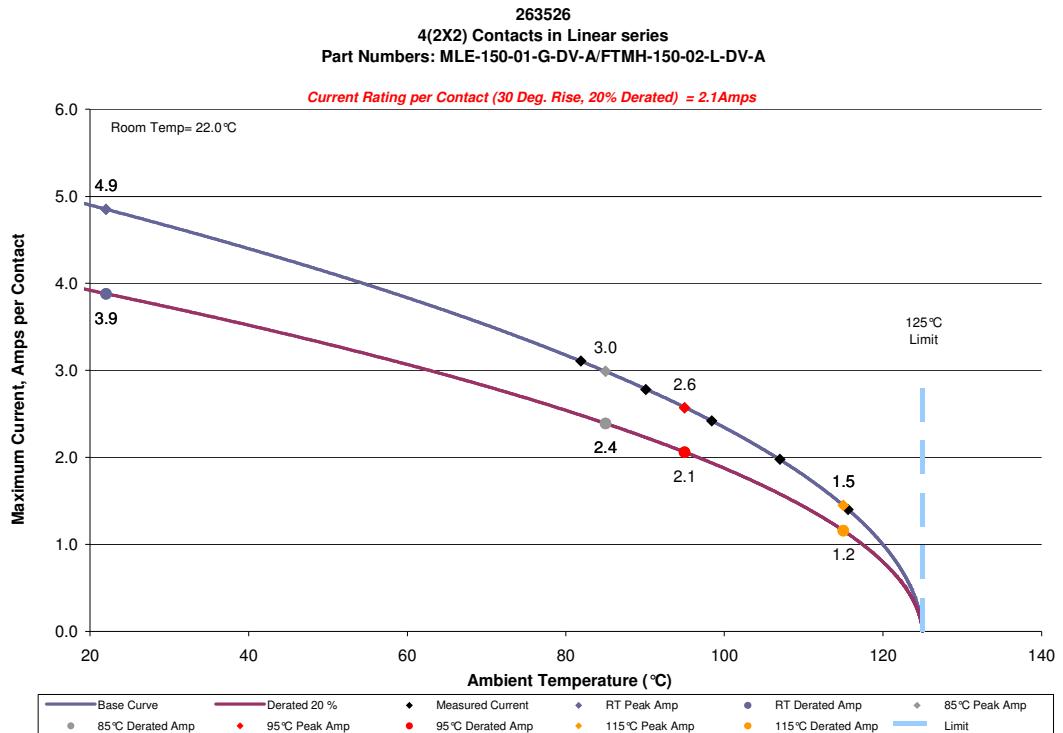
- 1) High quality thermocouples whose temperature slopes track one another were used for temperature monitoring.
- 2) The thermocouples were placed at a location to sense the maximum temperature generated during testing.
- 3) Temperature readings recorded are those for which three successive readings, 15 minutes apart, differ less than 1°C (computer controlled data acquisition).
- 4) Adjacent contacts were powered:
  - a. Linear configuration with 2 adjacent conductors/contacts powered





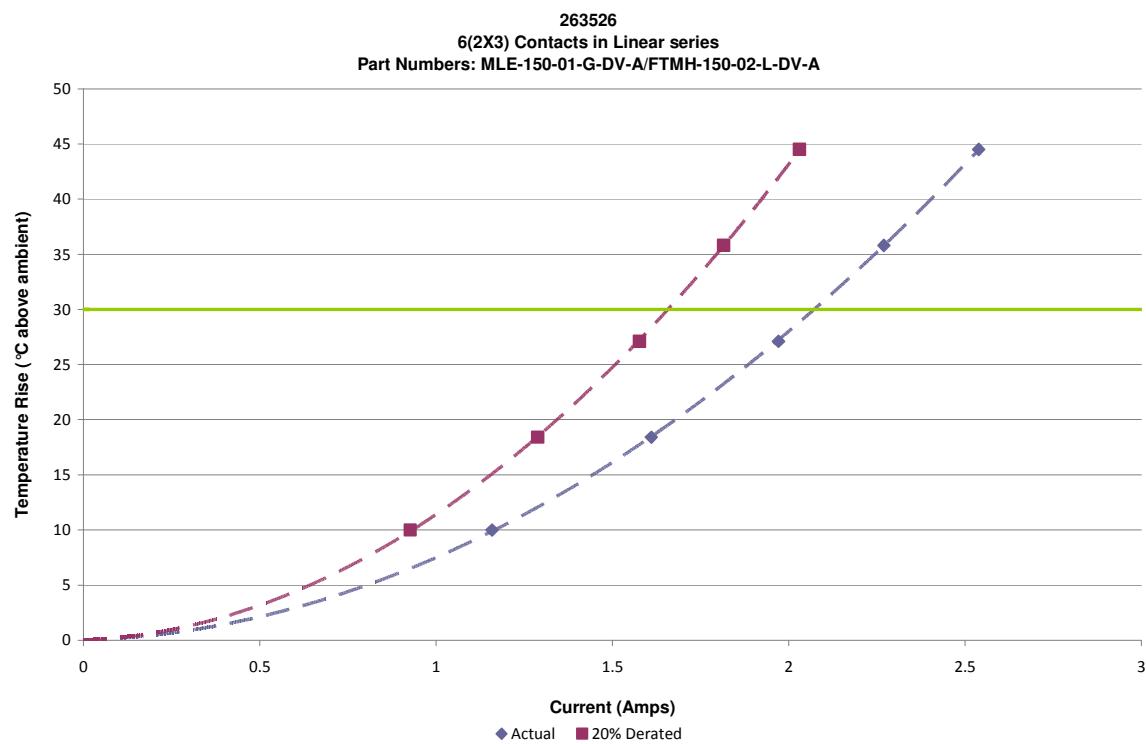
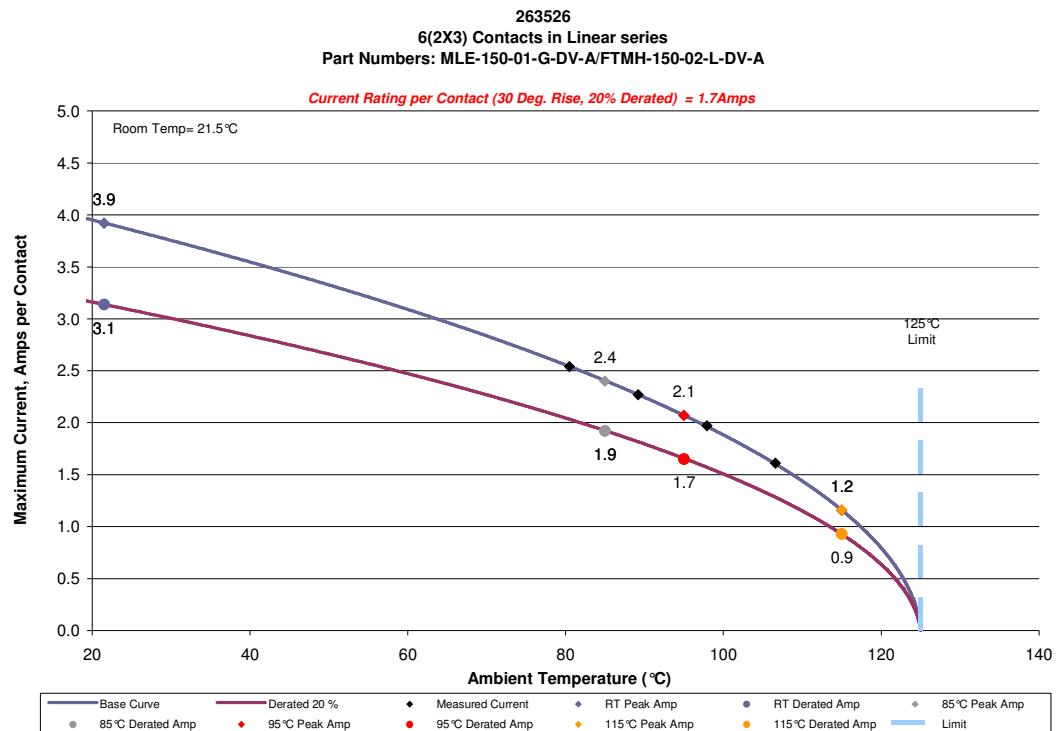
## DATA SUMMARIES Continued

b. Linear configuration with 4 adjacent conductors/contacts powered



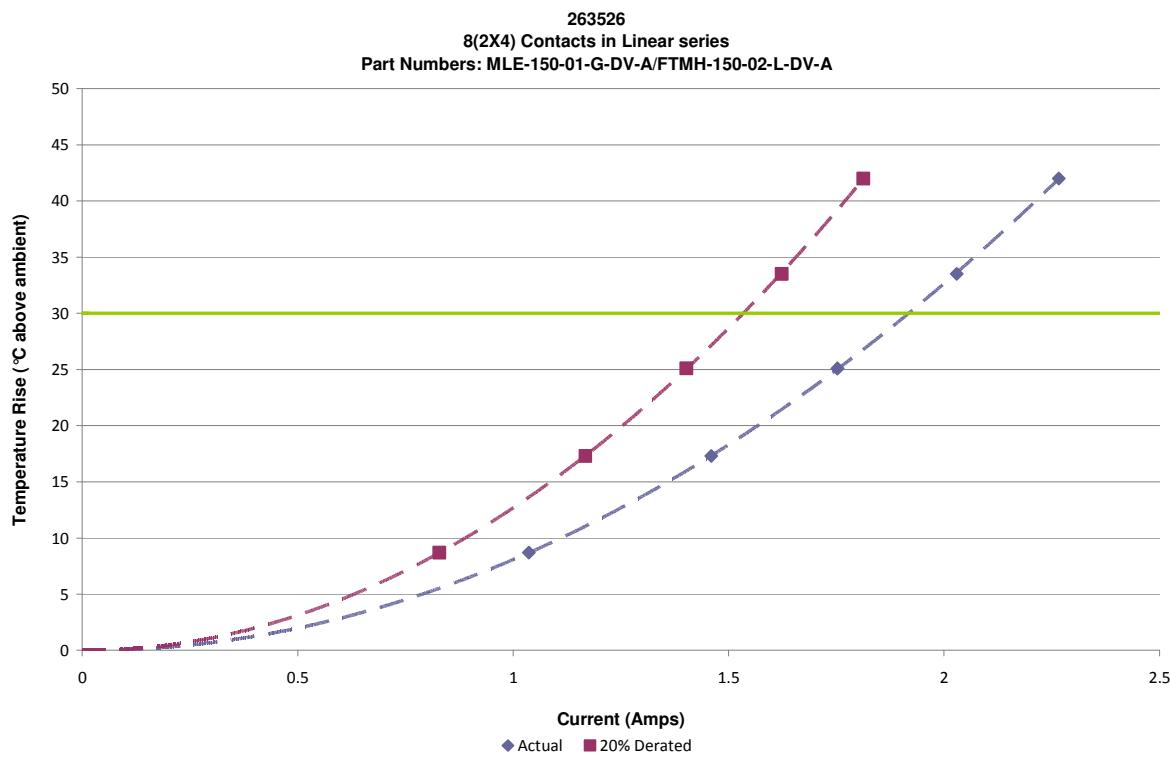
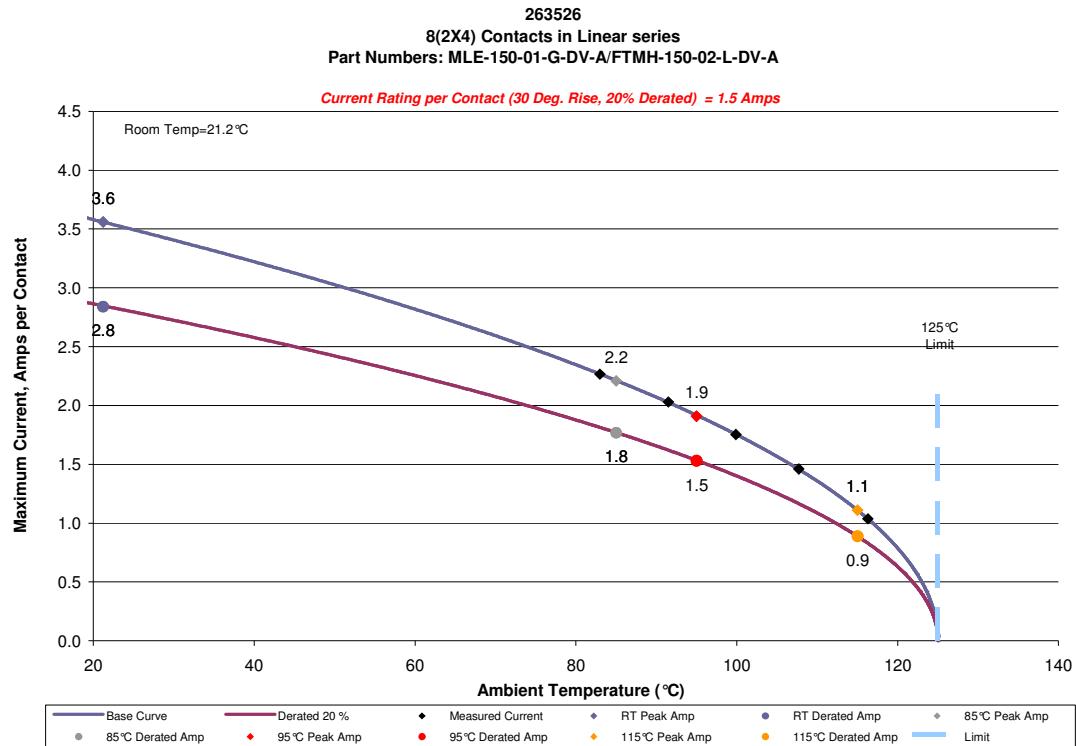
## DATA SUMMARIES Continued

c. Linear configuration with 6 adjacent conductors/contacts powered



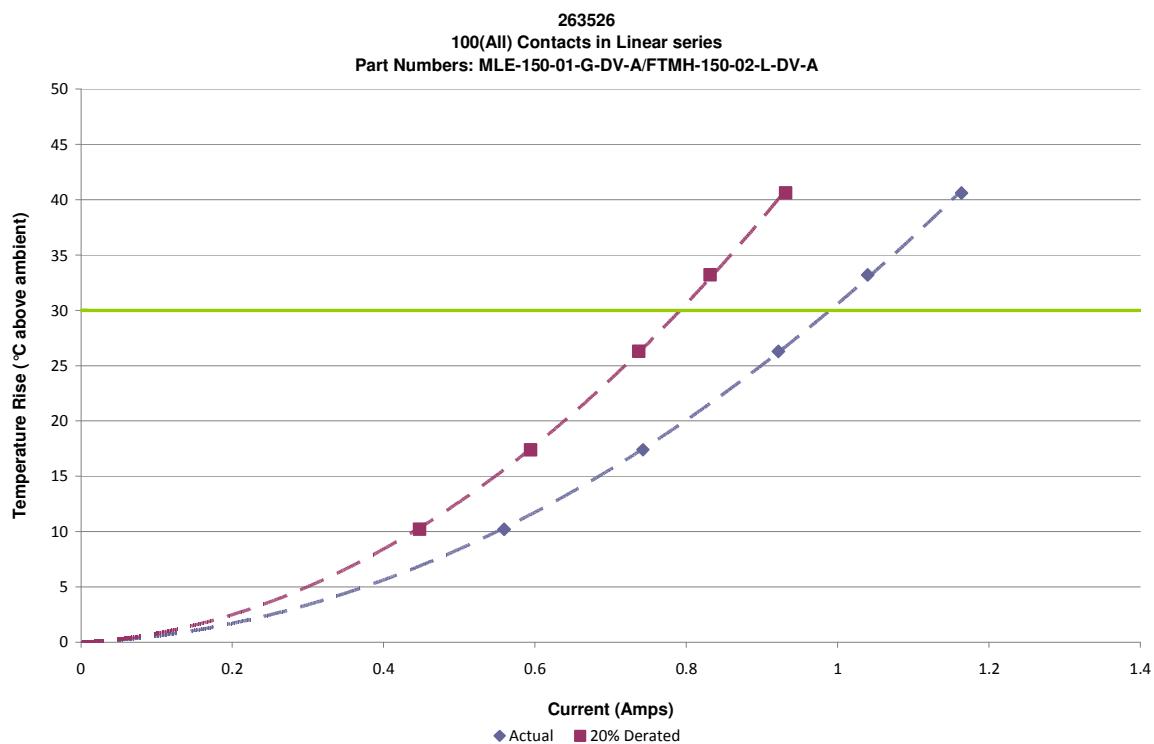
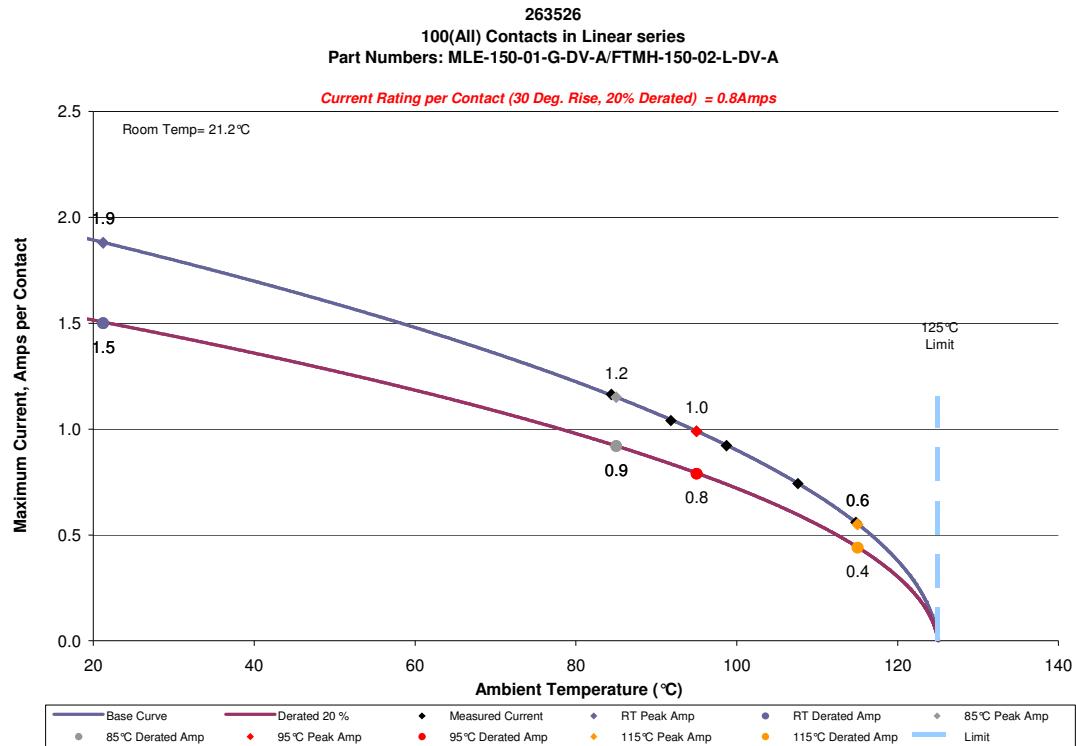
## DATA SUMMARIES Continued

d. Linear configuration with 8 adjacent conductors/contacts powered



## DATA SUMMARIES Continued

e. Linear configuration with all adjacent conductors/contacts powered



## DATA SUMMARIES Continued

## MATING-UNMATING FORCE:

## Thermal Aging Group

	Initial				After Thermals			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	15.12	3.40	6.94	1.56	9.96	2.24	5.52	1.24
Maximum	18.33	4.12	10.59	2.38	11.83	2.66	7.78	1.75
Average	16.98	<b>3.82</b>	8.22	<b>1.85</b>	10.92	<b>2.46</b>	6.59	<b>1.48</b>
St Dev	1.19	0.27	1.28	0.29	0.65	0.15	0.74	0.17
Count	8	8	8	8	8	8	8	8

## Mating-Unmating Durability Group

	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	13.26	<b>2.98</b>	6.94	1.56	14.10	3.17	9.21	2.07
Maximum	17.21	<b>3.87</b>	10.76	2.42	21.84	4.91	16.37	3.68
Average	15.17	<b>3.41</b>	8.42	<b>1.89</b>	17.31	<b>3.89</b>	12.42	<b>2.79</b>
St Dev	1.32	0.30	1.30	0.29	2.29	0.52	2.07	0.46
Count	8	8	8	8	8	8	8	8
	After 50 Cycles				After 75 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	14.23	3.20	9.74	2.19	14.28	3.21	10.81	2.43
Maximum	24.46	<b>5.50</b>	18.50	4.16	26.47	5.95	20.37	4.58
Average	18.61	<b>4.19</b>	14.30	<b>3.22</b>	19.97	<b>4.49</b>	15.75	<b>3.54</b>
St Dev	2.96	0.67	2.56	0.58	3.54	0.80	2.71	0.61
Count	8	8	8	8	8	8	8	8
	After 100 Cycles				After Humidity			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	14.86	3.34	10.94	2.46	9.96	2.24	6.72	1.51
Maximum	28.51	<b>6.41</b>	21.22	4.77	14.41	3.24	12.23	2.75
Average	21.78	<b>4.90</b>	17.08	<b>3.84</b>	12.05	<b>2.71</b>	9.30	<b>2.09</b>
St Dev	3.98	0.90	3.04	0.68	1.56	0.35	1.89	0.43
Count	8	8	8	8	8	8	8	8

## DATA SUMMARIES Continued

## MATING-UNMATING FORCE:

## Mating-Unmating Basic (MLE-150-01-G-DV-A/FTMH-150-02-L-DV-A)

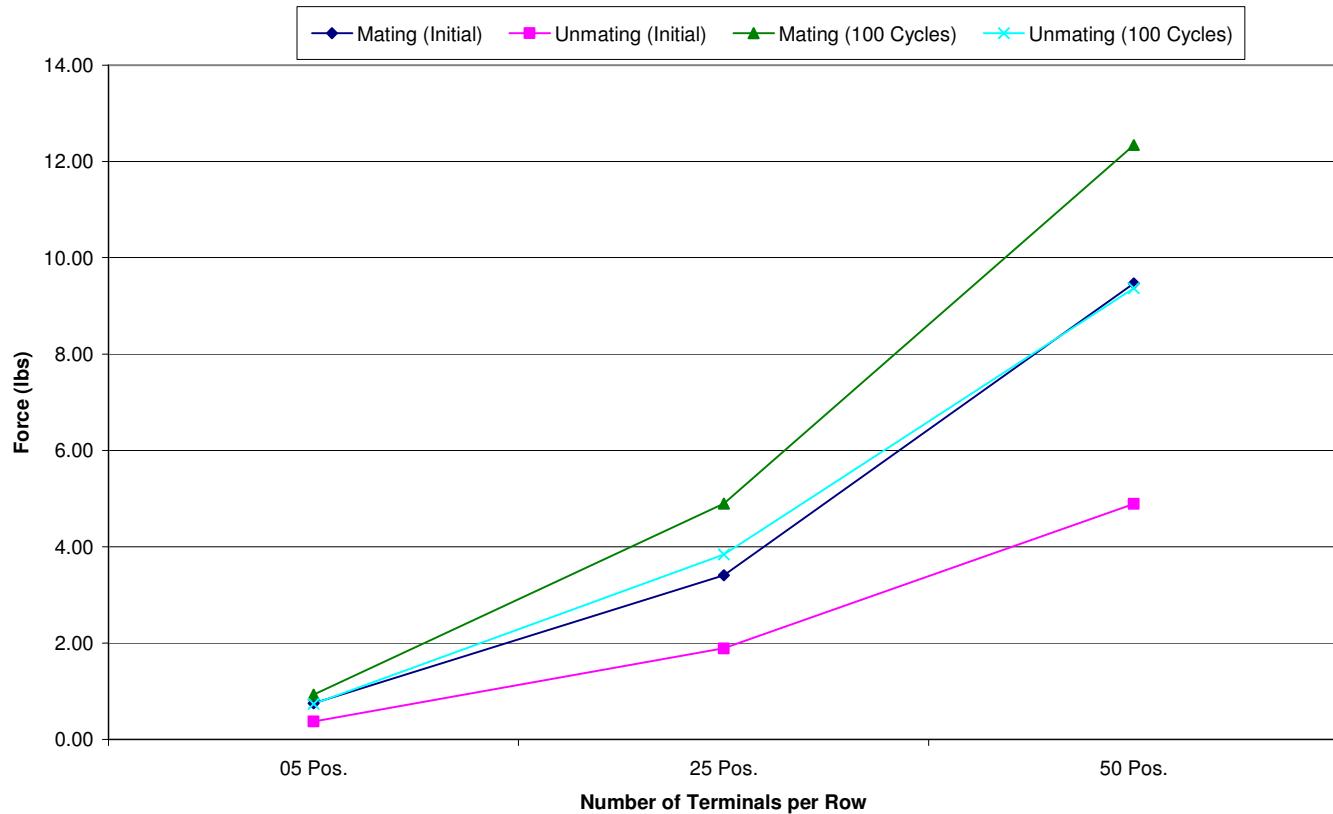
	Initial				After 25 Cycles			
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	38.12	8.57	18.01	4.05	39.77	8.94	28.38	6.38
Maximum	46.26	10.40	23.93	5.38	59.43	13.36	41.32	9.29
Average	42.11	<b>9.47</b>	21.74	<b>4.89</b>	47.12	<b>10.59</b>	33.74	<b>7.59</b>
St Dev	2.87	0.64	2.06	0.46	6.19	1.39	4.45	1.00
Count	8	8	8	8	8	8	8	8
After 50 Cycles				After 75 Cycles				
	Mating		Unmating		Mating		Unmating	
	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
	41.94	9.43	31.18	7.01	45.24	10.17	32.83	7.38
Minimum	41.94	9.43	31.18	7.01	45.24	10.17	32.83	7.38
Maximum	60.40	13.58	45.41	10.21	62.36	14.02	45.24	10.17
Average	48.87	<b>10.99</b>	36.81	<b>8.28</b>	52.33	<b>11.77</b>	39.39	<b>8.86</b>
St Dev	5.96	1.34	4.57	1.03	5.99	1.35	4.30	0.97
Count	8	8	8	8	8	8	8	8
After 100 Cycles								
	Mating		Unmating					
	Newton	Force (Lbs)	Newton	Force (Lbs)				
	47.19	10.61	34.29	7.71				
Minimum	47.19	10.61	34.29	7.71				
Maximum	65.43	14.71	48.17	10.83				
Average	54.89	<b>12.34</b>	41.66	<b>9.37</b>				
St Dev	6.42	1.44	4.47	1.00				
Count	8	8	8	8				

## DATA SUMMARIES Continued

## MATING-UNMATING FORCE:

## Mating-Unmating Basic (MLE-105-01-G-DV-A/FTMH-105-02-L-DV-A)

Initial				After 25 Cycles			
Mating		Unmating		Mating		Unmating	
Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	2.76	0.62	1.38	0.31	2.80	0.63	1.91
Maximum	3.74	0.84	1.87	0.42	3.96	0.89	2.94
<b>Average</b>	<b>3.34</b>	<b>0.75</b>	<b>1.63</b>	<b>0.37</b>	<b>3.51</b>	<b>0.79</b>	<b>2.43</b>
St Dev	0.37	0.08	0.16	0.04	0.46	0.10	0.35
Count	8	8	8	8	8	8	8
After 50 Cycles				After 75 Cycles			
Mating		Unmating		Mating		Unmating	
Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)	Newton	Force (Lbs)
Minimum	2.85	0.64	2.18	0.49	3.07	0.69	2.40
Maximum	4.18	0.94	3.20	0.72	4.45	1.00	3.60
<b>Average</b>	<b>3.69</b>	<b>0.83</b>	<b>2.78</b>	<b>0.63</b>	<b>3.91</b>	<b>0.88</b>	<b>2.98</b>
St Dev	0.48	0.11	0.33	0.08	0.52	0.12	0.43
Count	8	8	8	8	8	8	8
After 100 Cycles							
Mating		Unmating					
Newton	Force (Lbs)	Newton	Force (Lbs)				
Minimum	3.34	0.75	2.67	0.60			
Maximum	4.63	1.04	3.69	0.83			
<b>Average</b>	<b>4.13</b>	<b>0.93</b>	<b>3.27</b>	<b>0.74</b>			
St Dev	0.45	0.10	0.42	0.09			
Count	8	8	8	8			

**DATA SUMMARIES Continued****Mating\Unmating Force Comparison****Mating/Unmating Data for 05, 25 and 50 Position MLE/FTMH**

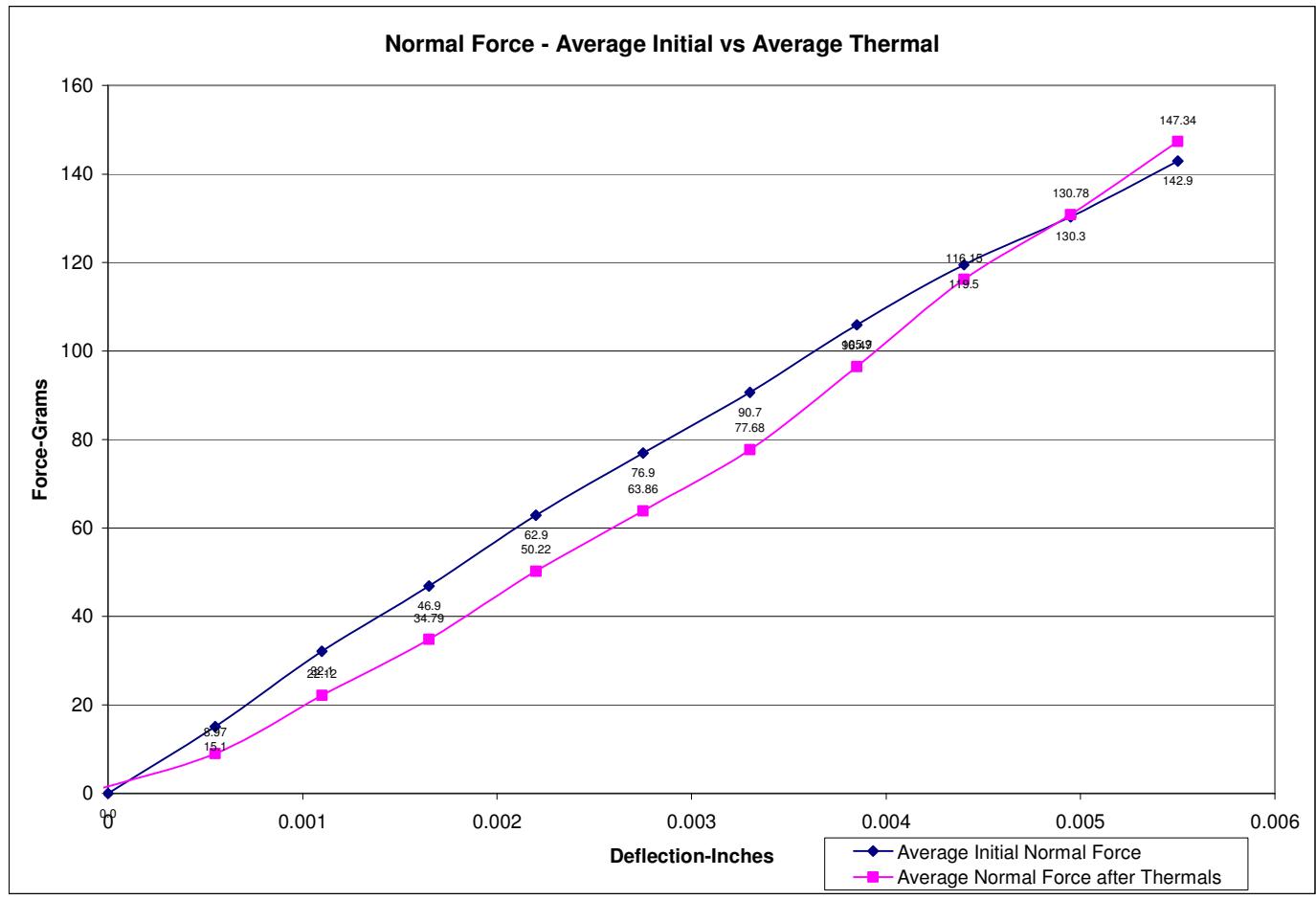
## DATA SUMMARIES Continued

### NORMAL FORCE (FOR CONTACTS TESTED IN THE HOUSING):

- 1) Calibrated force gauges are used along with computer controlled positioning equipment.
- 2) For Normal force 8-10 measurements are taken and the averages reported.

	Deflections in inches Forces in Grams										
	<b>Initial</b>	<b>0.0006</b>	<b>0.0011</b>	<b>0.0017</b>	<b>0.0022</b>	<b>0.0028</b>	<b>0.0033</b>	<b>0.0039</b>	<b>0.0044</b>	<b>0.0050</b>	<b>0.0055</b>
<b>Averages</b>	15.10	32.08	46.89	62.88	76.93	90.65	105.90	119.48	130.33	142.89	0.0005
<b>Min</b>	12.80	28.10	40.40	55.30	71.00	83.40	97.30	112.50	122.80	135.20	0.0003
<b>Max</b>	17.20	34.70	51.10	69.90	85.90	97.20	113.30	127.70	137.80	150.50	0.0008
<b>St. Dev</b>	1.257	2.076	3.704	4.505	4.576	4.353	5.283	5.389	4.980	4.922	0.0001
<b>Count</b>	12	12	12	12	12	12	12	12	12	12	12

After Thermals	Deflections in inches Forces in Grams										
	<b>0.0006</b>	<b>0.0011</b>	<b>0.0017</b>	<b>0.0022</b>	<b>0.0028</b>	<b>0.0033</b>	<b>0.0039</b>	<b>0.0044</b>	<b>0.0050</b>	<b>0.0055</b>	<b>SET</b>
<b>Averages</b>	8.97	22.12	34.79	50.22	63.86	77.68	96.47	116.15	130.78	147.34	0.0002
<b>Min</b>	-0.10	10.00	22.10	38.70	54.50	65.60	84.70	102.80	116.20	132.50	0.0000
<b>Max</b>	17.20	35.20	48.30	61.00	76.00	94.80	114.10	133.30	149.20	167.90	0.0007
<b>St. Dev</b>	5.336	7.123	7.293	7.371	7.887	10.771	10.403	11.083	11.363	11.354	0.0003
<b>Count</b>	12	12	12	12	12	12	12	12	12	12	12



**DATA SUMMARIES Continued****INSULATION RESISTANCE (IR):**

	Pin to Pin		
	Mated	Unmated	Unmated
Minimum	MLE/FTMH	MLE	FTMH
<b>Initial</b>	10000	10000	10000
<b>Thermal</b>	10000	10000	10000
<b>Humidity</b>	10000	10000	10000

	Row to Row		
	Mated	Unmated	Unmated
Minimum	MLE/FTMH	MLE	FTMH
<b>Initial</b>	10000	10000	10000
<b>Thermal</b>	10000	10000	10000
<b>Humidity</b>	10000	10000	10000

**DIELECTRIC WITHSTANDING VOLTAGE (DWV):**

Voltage Rating Summary	
Minimum	MLE/FTMH
<b>Break Down Voltage</b>	1250
<b>Test Voltage</b>	938
<b>Working Voltage</b>	310

Pin to Pin	
<b>Initial Test Voltage</b>	Passed
<b>After Thermal Test Voltage</b>	Passed
<b>After Humidity Test Voltage</b>	Passed

Row to Row	
<b>Initial Test Voltage</b>	Passed
<b>After Thermal Test Voltage</b>	Passed
<b>After Humidity Test Voltage</b>	Passed

## DATA SUMMARIES Continued

### LLCR Thermal Aging Group

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms: ----- Stable
  - b.  $+5.1$  to  $+10.0$  mOhms: ----- Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: ----- Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: ----- Marginal
  - e.  $+50.1$  to  $+2000$  mOhms ----- Unstable
  - f.  $>+2000$  mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type							
Date	2013-9-22	2013-10-8					
	Room Temp (Deg C)	25	24				
Rel Humidity (%)		55	56				
Technician		Kason He	Kason He				
mOhm values		Actual	Delta	Delta	Delta		
Average	Initial	Thermal					
			Pin Type 1: Signal				
St. Dev.		10.74	0.57				
Min		1.04	0.61				
Max		9.05	0.00				
Summary Count		14.37	3.26				
Total Count		192	192				
		192	192				

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	$\leq 5$	$>5 \text{ & } \leq 10$	$>10 \text{ & } \leq 15$	$>15 \text{ & } \leq 50$	$>50 \text{ & } \leq 1000$	$>1000$
Thermal	192	0	0	0	0	0

## DATA SUMMARIES Continued

### LLCR Mating/Unmating Durability Group

- 1). A total of 192 points were measured.
- 2). EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3). A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4). The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a. <= +5.0 mOhms: ----- Stable
  - b. +5.1 to +10.0 mOhms: ----- Minor
  - c. +10.1 to +15.0 mOhms: ----- Acceptable
  - d. +15.1 to +50.0 mOhms: ----- Marginal
  - e. +50.1 to +2000 mOhms ----- Unstable
  - f. > +2000 mOhms: ----- Open Failure

<b>LLCR Measurement Summaries by Pin Type</b>				
Date	2013-9-22	2013-9-25	2013-10-8	2013-10-25
	25	25	24	22
Room Temp (Deg C)	55	56	56	44
	Kason He	Kason He	Kason He	Kason He
mOhm values	Actual Initial	Delta 100 Cycles	Delta Therm Shck	Delta Humidity
	<b>Pin Type 1: Signal</b>			
Average	10.61	1.34	1.08	1.77
St. Dev.	0.90	1.59	1.35	1.87
Min	8.89	0.01	0.00	0.01
Max	13.59	9.42	8.56	9.01
Summary Count	192	192	192	192
Total Count	192	192	192	192

<b>LLCR Delta Count by Category</b>						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	<=5	>5 & <=10	>10 & <=15	>15 & <=50	>50 & <=1000	>1000
100 Cycles	183	9	0	0	0	0
Therm Shck	186	6	0	0	0	0
Humidity	173	19	0	0	0	0

## DATA SUMMARIES Continued

### LLCR Gas Tight Group

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms: ----- Stable
  - b.  $+5.1$  to  $+10.0$  mOhms: ----- Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: ----- Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: ----- Marginal
  - e.  $+50.1$  to  $+2000$  mOhms: ----- Unstable
  - f.  $>+2000$  mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type						
mOhm values	Date	2013-9-18	2013-9-18			
	Room Temp (Deg C)	23	23			
	Rel Humidity (%)	53	56			
	Technician	Kason He	Kason He			
	Actual	Delta		Delta	Delta	
	Initial	Acid Vapor				
	Pin Type 1: Signal					
	Average	10.72	1.58			
	St. Dev.	1.04	1.31			
	Min	8.84	0.00			
	Max	13.92	6.58			
	Summary Count	192	192			
	Total Count	192	192			

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	$\leq 5$	$>5 \text{ & } \leq 10$	$>10 \text{ & } \leq 15$	$>15 \text{ & } \leq 50$	$>50 \text{ & } \leq 1000$	$>1000$
Acid Vapor	190	2	0	0	0	0

## DATA SUMMARIES Continued

### LLCR Shock & Vibration Group

- 1) A total of 192 points were measured.
- 2) EIA-364-23, *Low Level Contact Resistance Test Procedure for Electrical Connectors and Sockets*.
- 3) A computer program, *LLCR 221.exe*, ensures repeatability for data acquisition.
- 4) The following guidelines are used to categorize the changes in LLCR as a result from stressing.
  - a.  $\leq +5.0$  mOhms: ----- Stable
  - b.  $+5.1$  to  $+10.0$  mOhms: ----- Minor
  - c.  $+10.1$  to  $+15.0$  mOhms: ----- Acceptable
  - d.  $+15.1$  to  $+50.0$  mOhms: ----- Marginal
  - e.  $+50.1$  to  $+2000$  mOhms ----- Unstable
  - f.  $>+2000$  mOhms: ----- Open Failure

LLCR Measurement Summaries by Pin Type						
mOhm values	Date	2013-9-30	2013-11-1			
	Room Temp (Deg C)	21	22			
	Rel Humidity (%)	51	35			
	Technician	Aaron McKim	Tony Wagoner			
	Actual	Delta		Delta	Delta	
	Initial	Shock-Vib				
	Pin Type 1: Signal					
Average	9.37	0.09				
St. Dev.	0.35	0.09				
Min	8.71	0.00				
Max	10.41	0.46				
Summary Count	192	192				
Total Count	192	192				

LLCR Delta Count by Category						
mOhms	Stable	Minor	Acceptable	Marginal	Unstable	Open
	$\leq 5$	$>5 \text{ & } \leq 10$	$>10 \text{ & } \leq 15$	$>15 \text{ & } \leq 50$	$>50 \text{ & } \leq 1000$	$>1000$
Shock-Vib	192	0	0	0	0	0

### Nanosecond Event Detection:

Shock and Vibration Event Detection Summary	
Contacts tested	60
Test Condition	C, 100g's, 6ms, Half-Sine
Shock Events	0
Test Condition	V-B, 7.56 rms g
Vibration Events	0
Total Events	0

## EQUIPMENT AND CALIBRATION SCHEDULES

**Equipment #:** HZ-TCT-01

**Description:** Normal force analyzer

**Manufacturer:** Mecmesin Multitester

**Model:** Mecmesin Multitester 2.5-i

**Serial #:** 08-1049-04

**Accuracy:** Last Cal: 4/26/2013, Next Cal: 4/25/2014

**Equipment #:** HZ-OV-01

**Description:** Oven

**Manufacturer:** Huida

**Model:** CS101-1E

**Serial #:** CS101-1E-B

**Accuracy:** Last Cal: 12/13/2012, Next Cal: 12/12/2013

**Equipment #:** HZ-THC-01

**Description:** Humidity transmitter

**Manufacturer:** Thermtron

**Model:** SM-8-8200

**Serial #:** 38846

**Accuracy:** Last Cal: 2/28/2013, Next Cal: 2/27/2014

**Equipment #:** HZ-HPM-01

**Description:** NA9636H

**Manufacturer:** Ainuo

**Model:** 6031A

**Serial #:** 089601091

**Accuracy:** Last Cal: 3/7/2013, Next Cal: 3/6/2014

**Equipment #:** HZ-MO-05

**Description:** Micro-ohmmeter

**Manufacturer:** Keithley

**Model:** 3706

**Serial #:** 1285188

**Accuracy:** Last Cal: 11/15/2012, Next Cal: 11/14/2013

**Equipment #:** HZ-TSC-01

**Description:** Vertical Thermal Shock Chamber

**Manufacturer:** Cincinnati Sub Zero

**Model:** VTS-3-6-6-SC/AC

**Serial #:** 10-VT14994

**Accuracy:** See Manual

... Last Cal: 06/27/2013, Next Cal: 06/26/2014

**Equipment #:** HZ-PS-01

**Description:** 120 Amp Power Supply

**Manufacturer:** Agilent

**Model:** 6031A PS

**Serial #:** MY41000982

**Accuracy:** See Manual

... Last Cal: 07/02/2013, Next Cal: 07/01/2014

## EQUIPMENT AND CALIBRATION SCHEDULES Continued

**Equipment #:** HZ-MO-01

**Description:** Multimeter /Data Acquisition System

**Manufacturer:** Keithley

**Model:** 2700

**Serial #:** 1199807

**Accuracy:** See Manual

... Last Cal: 07/02/2013, Next Cal: 07/01/2014

**Equipment #:** MO-11

**Description:** Switch/Multimeter

**Manufacturer:** Keithley

**Model:** 3706

**Serial #:** 120169

**Accuracy:** See Manual

... Last Cal: 08/21/2013, Next Cal: 08/21/2014

**Equipment #:** SVC-01

**Description:** Shock & Vibration Table

**Manufacturer:** Data Physics

**Model:** LE-DSA-10-20K

**Serial #:** 10037

**Accuracy:** See Manual

... Last Cal: 11/31/2012, Next Cal: 11/31/2013

**Equipment #:** ACLM-01

**Description:** Accelerometer

**Manufacturer:** PCB Piezotronics

**Model:** 352C03

**Serial #:** 115819

**Accuracy:** See Manual

... Last Cal: 07/09/2014, Next Cal: 07/09/2014

**Equipment #:** ED-03

**Description:** Event Detector

**Manufacturer:** Analysis Tech

**Model:** 32EHD

**Serial #:** 1100604

**Accuracy:** See Manual

... Last Cal: 06/04/2013, Next Cal: 06/04/2014